

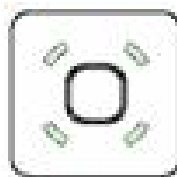
CE08U12P0S1

1-channel ultra low capacitance ESD diode

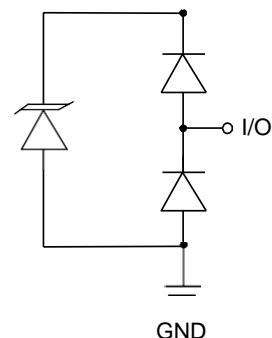
Wafer Information

Item	Description
Wafer Size	6 inch (150mm)
Wafer Thickness	150um ± 10um
Die Size (with scribe lane)	206um x 206um
Bond Pad Opening	72um x 72um
Scribe Lane Width	50um
Gross Die Per Wafer	357,000
Top Metal (for wire bond)	4μm AlSiCu
Backside Metal (for die bond)	Sn

Die Appearance



Circuit Diagram



- Complies with IEC 61000-4-2 standards:
Contact discharge: ±8kV

Absolute Maximum Ratings (T_A=25°C unless otherwise specified)

Parameter	Symbol	Value	Unit
Operating Temperature Range	T _J	-55 to +125	°C
Storage Temperature Range	T _{stg}	-55 to +150	°C

Electrical Characteristics (T_A=25°C unless otherwise specified)

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Parameter	Symbol	Min	Typ	Max	Unit	Test Condition
Reverse Working Voltage	VRWM			12	V	
Breakdown Voltage	VBR	13.2			V	IT = 1mA
Reverse Leakage Current	IR			100	nA	VRWM = 12V
Forward voltage	VF			1.2	V	IF=15mA
Clamping Voltage	VC			22	V	IPP = 1A (8 x 20μs pulse)
Clamping Voltage	VC			24	V	IPP = 1.8A (8 x 20μs pulse)
Junction Capacitance	C _J		0.45	0.60	pF	VR = 0V, f = 1MHz

Note: Electrical parameters are only for die, performance may alter after assembly.